

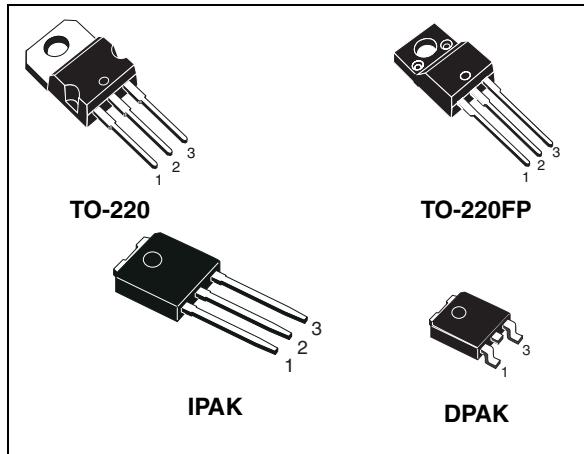
STD10NM60N, STF10NM60N STP10NM60N, STU10NM60N

N-channel 600 V, 0.53 Ω 10 A, DPAK, TO-220, TO-220FP, IPAK
MDmesh™ II Power MOSFET

Features

Order codes	V_{DSS} @ T_{Jmax}	$R_{DS(on)}$ max.	I_D	P_w
STD10NM60N	650 V	< 0.55 Ω	10 A	70 W
STF10NM60N				25 W
STP10NM60N				70 W
STU10NM60N				

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



Application

Switching applications

Description

These devices are N-channel 600 V Power MOSFET realized using the second generation of MDmesh™ technology. It applies the benefits of the multiple drain process to STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product offers improved on-resistance, low gate charge, high dv/dt capability and excellent avalanche characteristics.

Figure 1. Internal schematic diagram

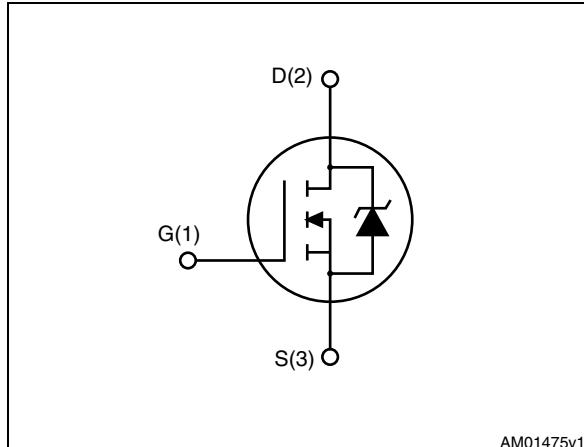


Table 1. Device summary

Order codes	Marking	Package	Packaging
STD10NM60N	10NM60N	DPAK	Tape and reel
STF10NM60N	10NM60N	TO-220FP	Tube
STP10NM60N	10NM60N	TO-220	Tube
STU10NM60N	10NM60N	IPAK	Tube

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value				Unit
		TO-220	TO-220FP	IPAK	DPAK	
V_{GS}	Gate- source voltage	± 25				V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	10	10 ⁽¹⁾	10	10	A
I_D	Drain current (continuous) at $T_C = 100^\circ\text{C}$	5	5 ⁽¹⁾	5	5	A
$I_{DM}^{(2)}$	Drain current (pulsed)	32	32 ⁽¹⁾	32	32	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	70	25	70	70	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15				V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t=1\text{ s}; T_C=25^\circ\text{C}$)		2500			V
T_J T_{stg}	Operating junction temperature Storage temperature	- 55 to 150				°C

1. Limited only by maximum temperature allowed.
2. Pulse width limited by safe operating area.
3. $I_{SD} \leq 10\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, V_{DS} peak $\leq V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$.

Table 3. Thermal data

Symbol	Parameter	Value				Unit
		TO-220	TO-220FP	IPAK	DPAK	
$R_{thj-case}$	Thermal resistance junction-case max	1.79	5	1.79	1.79	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.50	100			°C/W
$R_{thj-pcb}$	Thermal resistance junction-pcb max			50	50	°C/W
T_J	Maximum lead temperature for soldering purpose	300				°C/W

Table 4. Avalanche characteristics

Symbol	Parameter	Value		Unit
I_{AS}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_j Max)	4		A
E_{AS}	Single pulse avalanche energy (starting $T_j=25^\circ\text{C}$, $I_D=I_{AS}$, $V_{DD}=50\text{ V}$)	200		mJ

2 Electrical characteristics

(T_{case} =25 °C unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = max rating V _{DS} = max rating, T _C =125 °C			1 100	µA µA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V; V _{DS} =0			100	nA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250 µA	2	3	4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 4 A		0.53	0.55	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 50 V, f = 1 MHz, V _{GS} = 0	-	540 44 1.2	-	pF pF pF
C _{oss eq} ⁽¹⁾	Equivalent capacitance time related	V _{DS} = 0 to 480 V, V _{GS} = 0	-	110	-	pF
R _g	Gate input resistance	f=1 MHz open drain	-	6	-	Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 480 V, I _D = 8 A, V _{GS} = 10 V	-	19 3 10	-	nC nC nC

1. C_{oss eq} time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 4 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	10		ns
t_r	Rise time			12		ns
$t_{d(off)}$	Turn-off-delay time			32	-	ns
t_f	Fall time			15		ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
I_{SD}	Source-drain current		-		8	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				32	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 8 \text{ A}, V_{GS} = 0$	-		1.3	V
t_{rr}	Reverse recovery time	$I_{SD} = 8 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$	-	250		ns
Q_{rr}	Reverse recovery charge			2.12		μC
I_{RRM}	Reverse recovery current			17		A
t_{rr}	Reverse recovery time	$I_{SD} = 8 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$	-	315		ns
Q_{rr}	Reverse recovery charge			2.6		μC
I_{RRM}	Reverse recovery current			16.5		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

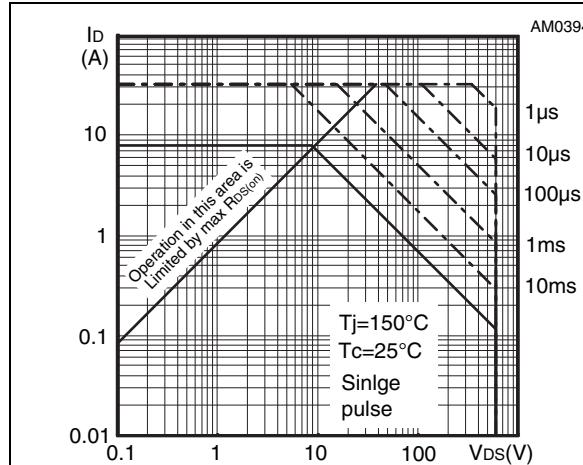


Figure 3. Thermal impedance for TO-220

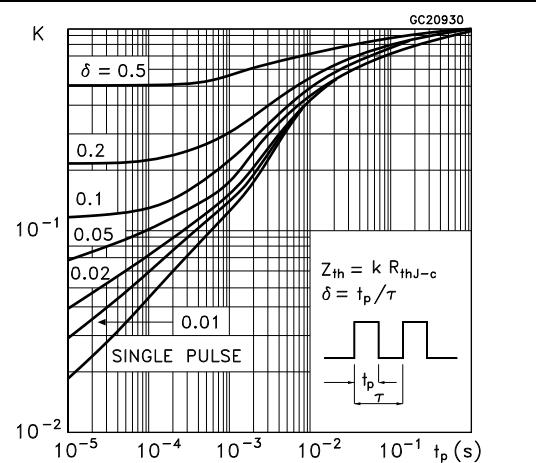


Figure 4. Safe operating area for TO-220FP

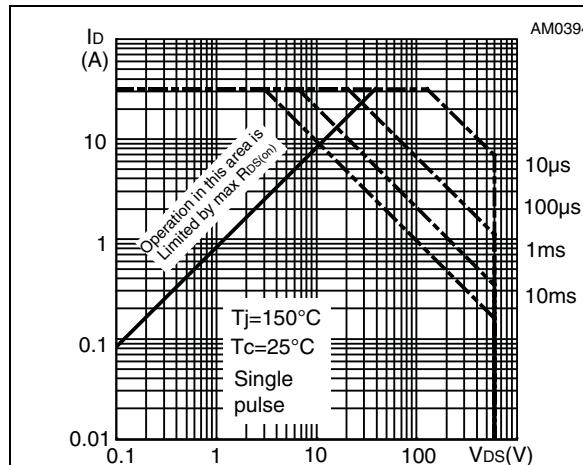


Figure 5. Thermal impedance for TO-220FP

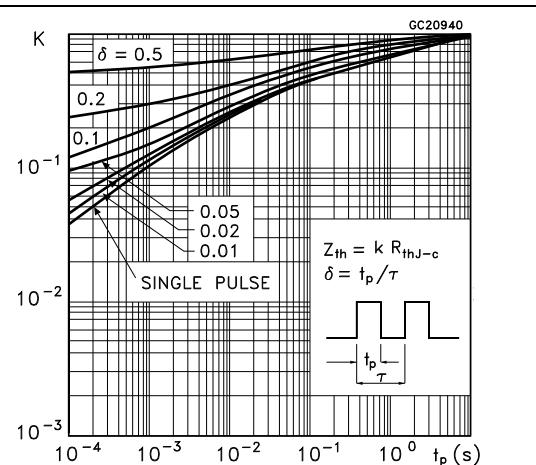


Figure 6. Safe operating area for DPAK, IPAK

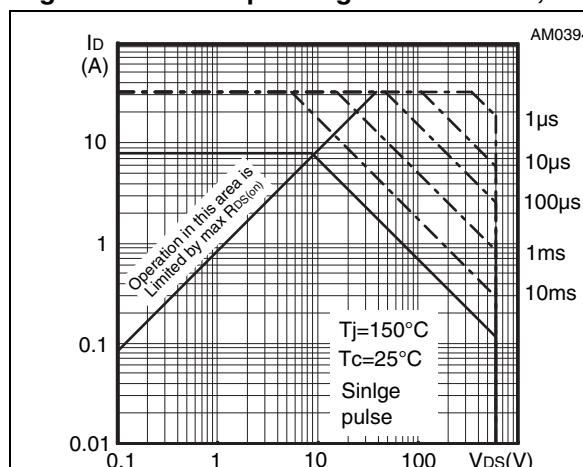


Figure 7. Thermal impedance for DPAK, IPAK

